

Table 1. Comparative characteristics of processors including radiation resistance

Producer	Processor	Fault tolerance	Scheme level of fault tolerance	System level of fault tolerance (liveness property ²)	Resistance to heavy ions	Clock frequency, MHz	Floating point arithmetic	Consumption, W	Performance in DS2.1 test, MIPS DMIPS	Specific performance, MIPS/W	Architecture	Dose, mrd	SEL LETth, MeV·cm ² /mg
BAE	RAD750	+	+		+	132	+	5	266	53	PowerPC 750	1	120
Aeroflex	UT699	+			+	66	+	5,5	75	14	SPARC V8	0,3	108
Intel	486DX	+				33	+	4,5	25	6			
AMD	Am29200	+				16		1,1	7	6			
Freescale	MPC555	+				40	+	1	62,59	63			
Motorola	MC68349	+				25		0,96	8	8			
Freescale	MCF5272	+				66		0,9	63	70			
ARM	ARM7500FE	+				40		0,8	36,4	46			
ARM	ARM7500	+				33		0,68	30	44			
ARM	ARM7TDMI	+				20		0,04	14	389			
MultiClet	MCp042L1	+	+	+	+	150	+	1,5	600	400	multicellular	>0,5⁴	>93^{4,5}
Atmel	AT697F	+						0,7	82	117	SPARC V8 Leon 2	0,3 ³	95
eASIC Corp	Leon4	+						5	340	68	SPARC V8	0,3	
Maxwell	750FX	+						12	600	50	PowerPC 750	0,1	92

The source of data comparison: A. Popovich. Protessor RAD750 v sistemah s ogranichennim byudzhedom mosh'nosti (Processor RAD750 in systems with limited capacity sources)/Komponenti i tehnologii (Components and Technologies)- 2010 - № 8 - pages 122-123.

¹ Scheme level of fault tolerance – in case of one majorized blocks failure, system is no more fault tolerant, but continues to perform

² System level of fault tolerance – when from 1 to 3 cells get out of order, system with its full functionality continue to perform, thus with a gradual performance degradation

³ Source: AT697F Rad-Hard 32 bit SPARC V8 Processor Complete/<http://www.atmel.com/Images/doc7703.pdf>

⁴ Data are based on test results for special triple logic libraries, which will be included in the processor. Sign ">" (more than) is the expected parameter increase due to liveness property

⁵ The maximum value at which the tests were conducted, thyristor effect attainment failed.